

Notice of References Cited	Application/Control No. 10/648,399	Applicant(s)/Patent Under Reexamination SATO ET AL.	
	Examiner Anita K. Alanko	Art Unit 1765	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US- 6,649,138 B2	11-2003	Adams et al.	423/203
	B	US- 6,911,082 B2	06-2005	Sato et al.	117/68
	C	US-2003/0228761 A1	12-2003	Sato et al.	438/689
	D	US-6,179,912 B1	01-2001	Barbera-Guillem et al.	117/68
	E	US-6,410,935 B1	06-2002	Rajh et al.	257/43
	F	US-6,607,829 B1	08-2003	Bawendi et al.	428/403
	G	US-6,788,453 B2	09-2004	Banin et al.	359/342
	H	US-6,906,339 B2	06-2005	Dutta, Partha	257/40
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004008982 A	01-2004	Japan	SATO et al.	B01J 19/00
	O	JP 2004352594 A	12-2004	Japan	SATO et al.	C01G 11/02
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Torimoto, T. et al, J.Phys. Chem B, "Characterization of Ultrasmall CdS Nanoparticles Prepared by teh Size-Selective Photoetching Technique" June 2001, Vol.105, pp 6838-6845.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.